

			02.11.2011
RefMat No 39 Category 1 Critical Dimensions			
	COMAR		Category 2 Single Step
	47.568 × 122-5-75	Included in DMAR Database:	Category 3 Lateral (X-Y-axis, 1-dim)
	7.3	Green 1> YES Blue 0> NO	Category 4
Category 5			
Type_of_RefMat: RM			
Name of RM: Surface Topography References (STR)			
Description  Surface Topography References (STR) combination of step height and pitch to enable three-dimensional calibration of optical interferometric microscopes and AFMs.  Link  http://www.vlsistandards.com/products/dimensional/streferences.asp?sid=31			
Certified Qantities			
	step height	MeanValue	18 nm Uncertainty
	step height	Mean Value	44 nm Uncertainty
	lateral distance	MeanValue	100 nm Uncertainty
,	lateral distance	MeanValue	180 nm Uncertainty
		MeanValue	nm Uncertainty
Calibration of Calibration of Calibration of Calibration of Calibration of	AFM SEM Interferometer WLIM		Characterised by Characterised by Characterised by Characterised by Characterised by Characterised by
2 Provider No 3  Web address http://www.vlsistandards.com			
Provider No Provider			
i iovidel	VLSI Standards, Inc.	Occupation	LIOA
Contact Person	Marc Helvey, ext. 108	Country	USA Son Jose
Email	sales.support@vlsistd.com	City Code	San Jose CA 95134-2006
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		0.1001 110	OSSA MORITI II ST ORIGOT